

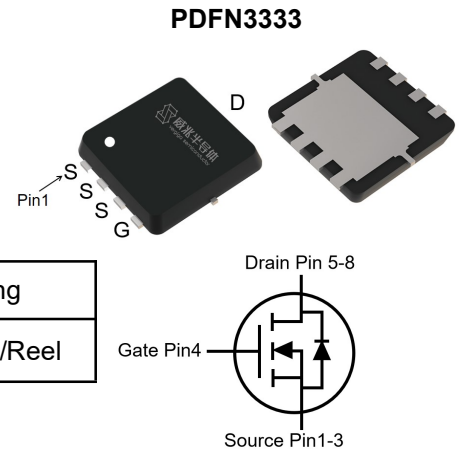
Features

- Enhancement mode
- Very low on-resistance
- VitoMOS® II Technology
- 100% Avalanche Tested, 100% Rg Tested

V_{DS}	30	V
$R_{DS(on),TYP@ V_{GS}=10V}$	4.2	mΩ
$R_{DS(on),TYP@ V_{GS}=4.5V}$	7.3	mΩ
$I_D(\text{Silicon Limited})$	48	A
$I_D(\text{Package Limited})$	36	A



Part ID	Package Type	Marking	Packing
VSE006N03MSC-G	PDFN3333	006N03M	5000PCS/Reel



Maximum ratings, at $T_A = 25^\circ\text{C}$, unless otherwise specified

Symbol	Parameter		Rating	Unit
V(BR)DSS	Drain-Source breakdown voltage		30	V
VGS	Gate-Source voltage		±20	V
IS	Diode continuous forward current (Silicon limited)	TC = 25°C	16	A
ID	Continuous drain current @VGS=10V (Silicon limited)	TC = 25°C	48	A
ID	Continuous drain current @VGS=10V (Silicon limited)	TC = 100°C	30	A
ID	Continuous drain current @VGS=10V (Wire bond limited)	TC = 25°C	36	A
IDM	Pulse drain current tested ①	TC = 25°C	192	A
IDSM	Continuous drain current @VGS=10V	TA = 25°C	17	A
		TA = 70°C	13	A
EAS	Avalanche energy, single pulsed ②		72	mJ
PD	Maximum power dissipation ③	TC = 25°C	19	W
		TC = 100°C	7.5	W
PDSM	Maximum power dissipation ④	TA = 25°C	2.3	W
		TA = 70°C	1.5	W
TSTG,TJ	Storage and Junction Temperature Range		-55 to 150	°C

Thermal Characteristics

Symbol	Parameter	Typical	Max	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case ⑤	5.6	6.7	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient ⑥	46	55	$^\circ\text{C/W}$

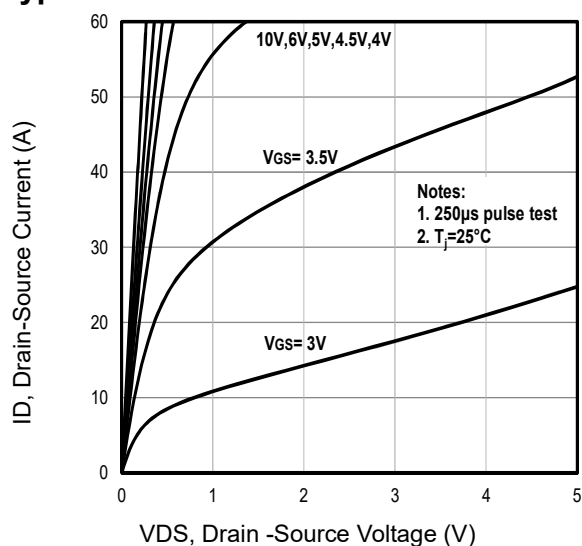
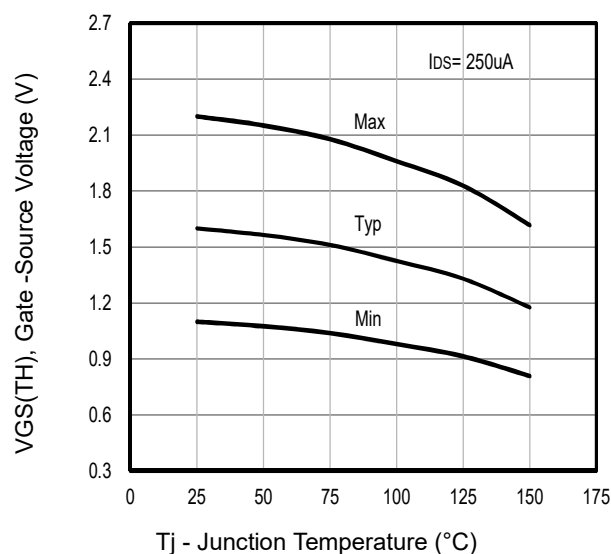
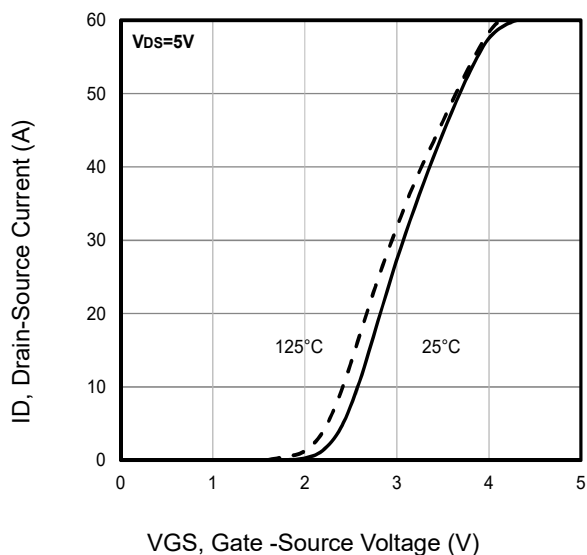
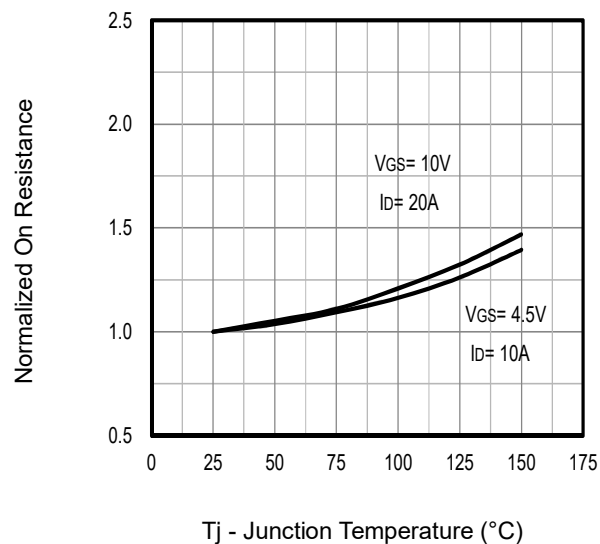
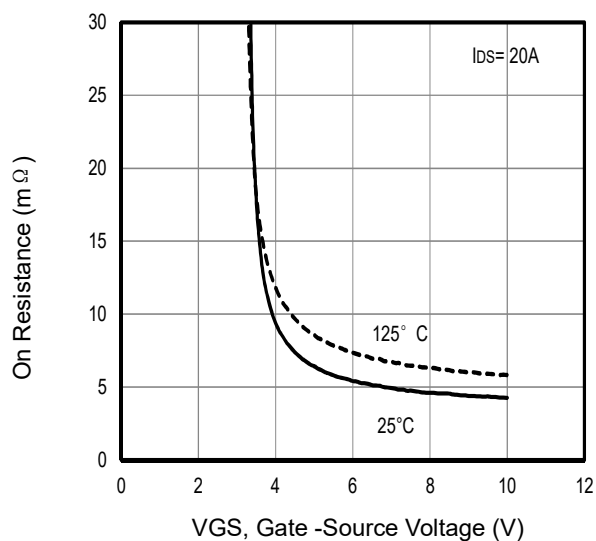
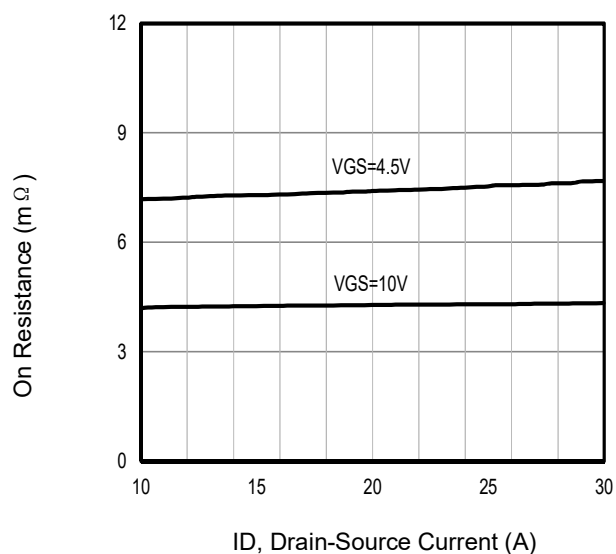
Electrical Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Unit
Static Electrical Characteristics @ T _j =25°C (unless otherwise stated)						
V(BR)DSS	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	30	--	--	V
I _{DSS}	Zero Gate Voltage Drain Current(T _j =25°C)	V _{DS} =30V,V _{GS} =0V	--	--	1	μA
	Zero Gate Voltage Drain Current(T _j =125°C)⑦	V _{DS} =30V,V _{GS} =0V	--	--	100	μA
I _{GSS}	Gate-Body Leakage Current	V _{GS} =±20V,V _{DS} =0V	--	--	±100	nA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} ,I _D =250μA	1.1	1.6	2.2	V
R _{DS(on)}	Drain-Source On-State Resistance ⑧	V _{GS} =10V, I _D =20A	--	4.2	5.5	mΩ
		(T _j =100°C)⑦	--	5.2	--	mΩ
R _{DS(on)}	Drain-Source On-State Resistance ⑧	V _{GS} =4.5V, I _D =10A	--	7.3	9.5	mΩ
Dynamic Electrical Characteristics @ T _j = 25°C (unless otherwise stated)						
C _{iss}	Input Capacitance ⑦	V _{DS} =15V,V _{GS} =0V, f=1MHz	415	825	1445	pF
C _{oss}	Output Capacitance ⑦		230	465	810	pF
C _{rss}	Reverse Transfer Capacitance ⑦		25	50	85	pF
R _g	Gate Resistance	f=1MHz	0.2	1	3	Ω
Q _g (10V)	Total Gate Charge ⑦	V _{DS} =15V,I _D =20A, V _{GS} =10V	--	15	26	nC
Q _g (4.5V)	Total Gate Charge ⑦		--	7.4	13	nC
Q _{gs}	Gate-Source Charge ⑦		--	2.8	4.9	nC
Q _{gd}	Gate-Drain Charge ⑦		--	2.8	4.9	nC
Switching Characteristics ⑦						
T _d (on)	Turn-on Delay Time	V _{DD} =15V, I _D =20A, R _G =3Ω, V _{GS} =10V	--	5.8	--	ns
T _r	Turn-on Rise Time		--	59	--	ns
T _d (off)	Turn-Off Delay Time		--	14	--	ns
T _f	Turn-Off Fall Time		--	8.8	--	ns
Source- Drain Diode Characteristics@ T _j = 25°C (unless otherwise stated)						
V _{SD}	Forward on voltage	I _{SD} =20A,V _{GS} =0V	--	0.8	1.2	V
T _{rr}	Reverse Recovery Time ⑦	I _{sd} =20A, V _{GS} =0V	--	15	30	ns
Q _{rr}	Reverse Recovery Charge ⑦	di/dt=100A/μs	--	2.8	5.6	nC

NOTE:

- ① Single pulse; pulse width $\leq 100\mu s$.
- ② EAS of 72mJ is based on starting $T_j = 25^{\circ}\text{C}$, $L = 0.5\text{mH}$, $R_G = 25\Omega$, $I_{AS} = 17A$, $V_{GS} = 10V$; 100% FT tested at $L = 0.5\text{mH}$, $I_{AS} = 9A$.
- ③ The power dissipation P_d is based on $T_j(\text{max})$, using junction-to-case thermal resistance $R_{\theta JC}$.
- ④ The power dissipation P_{dsm} is based on $T_j(\text{max})$, using junction-to-ambient thermal resistance $R_{\theta JA}$.
- ⑤ These tests are performed respectively with the device mounted on a 1 in2 pad and a minimum pad of 2oz. Copper FR-4 board in a still air environment with $T_A=25^{\circ}\text{C}$, using Transient Dual Interface method to acquire $R_{\theta JC}$.
- ⑥ These tests are performed with the device mounted on 1 in2 FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^{\circ}\text{C}$.
- ⑦ Guaranteed by design, not subject to production testing.
- ⑧ Pulse width $\leq 380\mu s$; duty cycles $\leq 2\%$.

Typical Characteristics


Fig1. Typical Output Characteristics

Fig2. Typical $V_{GS(TH)}$ Gate-Source Voltage Vs. T_j

Fig3. Typical Transfer Characteristics

Fig4. Typical Normalized On-Resistance Vs. T_j

Fig5. Typical On Resistance Vs Gate-Source Voltage

Fig6. Typical On Resistance Vs Drain Current

Typical Characteristics

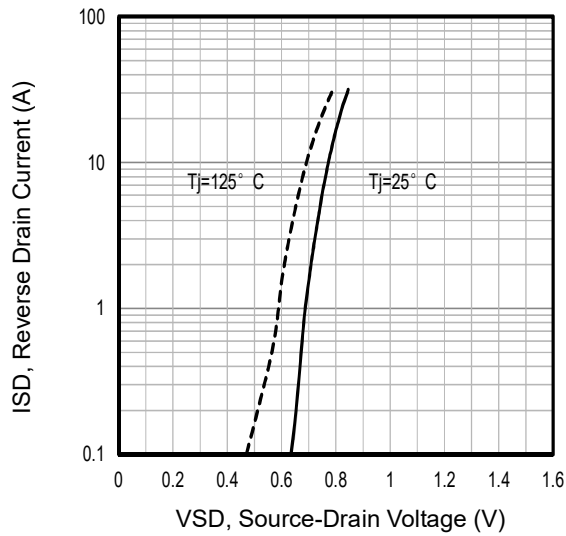


Fig7. Typical Source-Drain Diode Forward Voltage

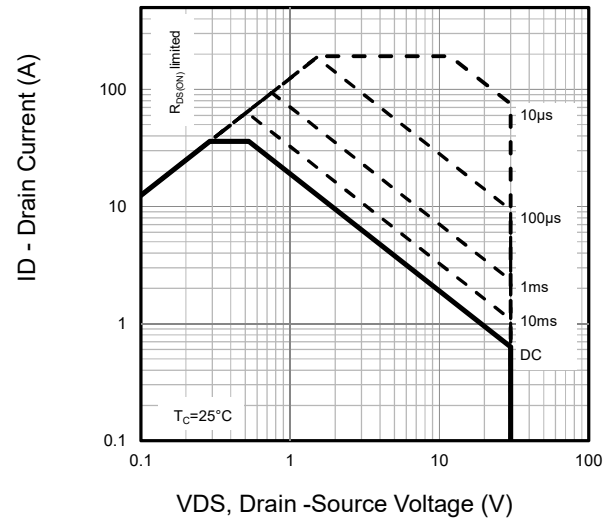


Fig8. Maximum Safe Operating Area

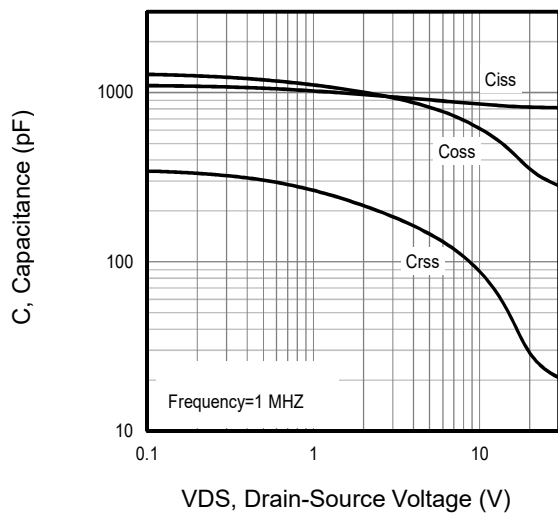


Fig9. Typical Capacitance Vs. Drain-Source Voltage

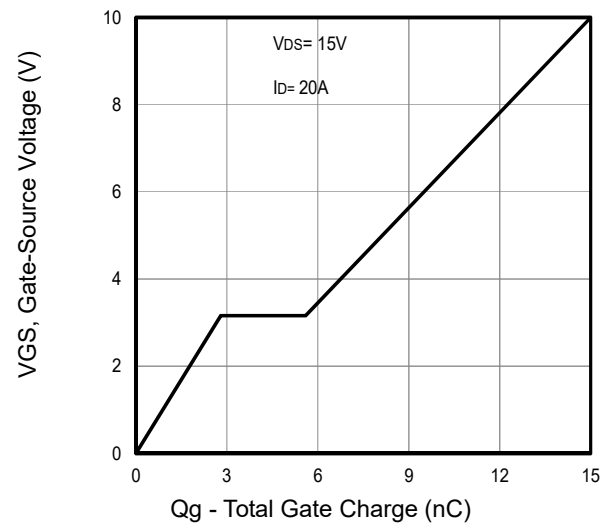


Fig10. Typical Gate Charge Vs. Gate-Source Voltage

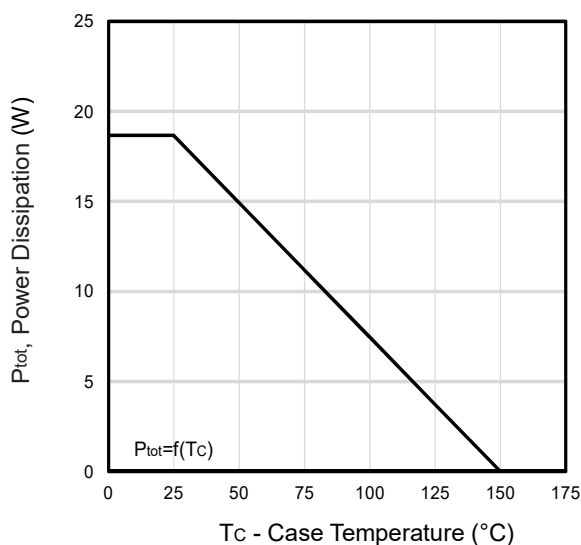


Fig11. Power Dissipation Vs. Case Temperature

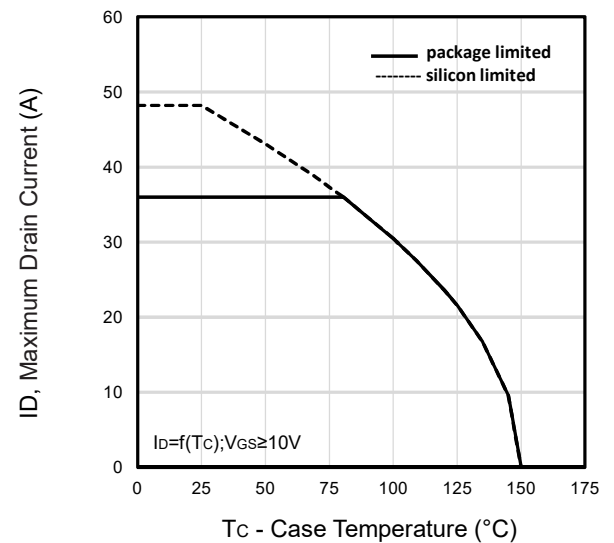


Fig12. Maximum Drain Current Vs. Case Temperature

Typical Characteristics

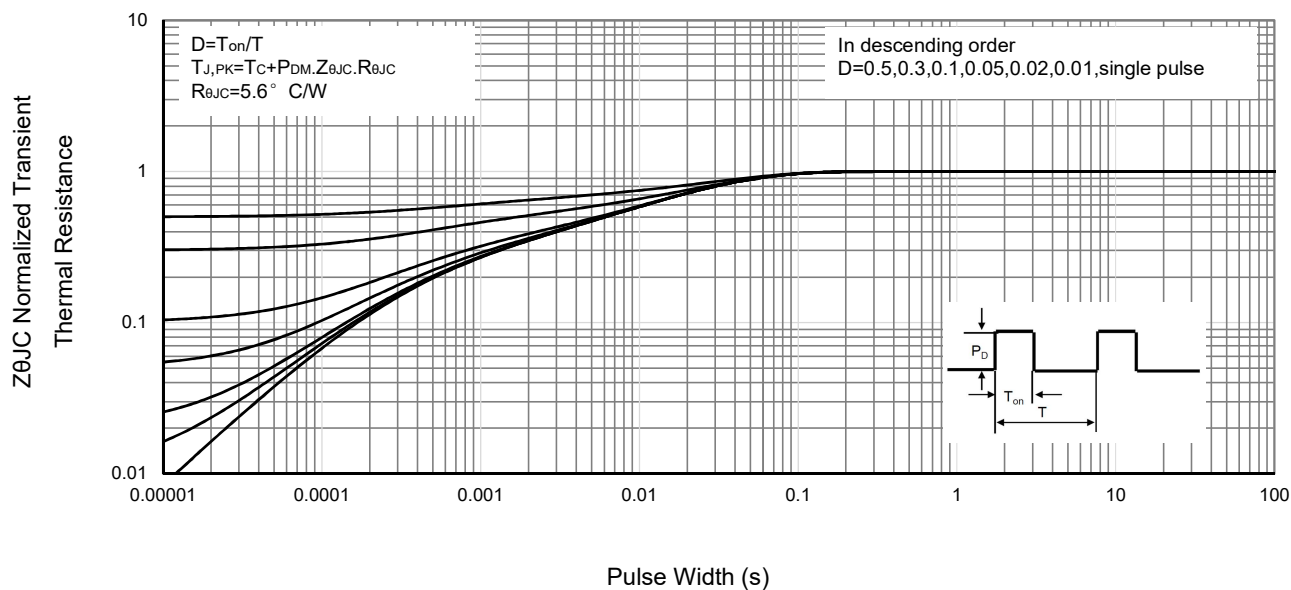


Fig13 . Normalized Maximum Transient Thermal Impedance

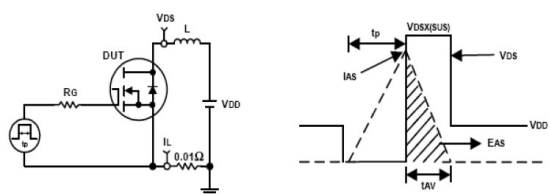


Fig14. Unclamped Inductive Test Circuit and waveforms

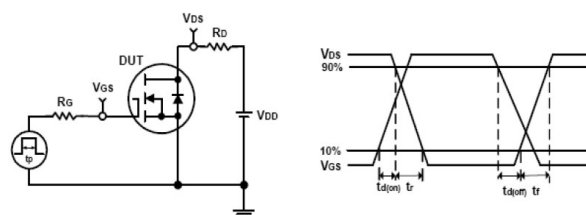
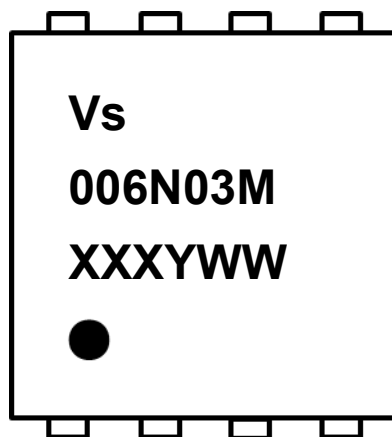


Fig15. Switching Time Test Circuit and waveforms

Marking Information



1st line: Vergiga Code (Vs)

2nd line: Part Number (006N03M)

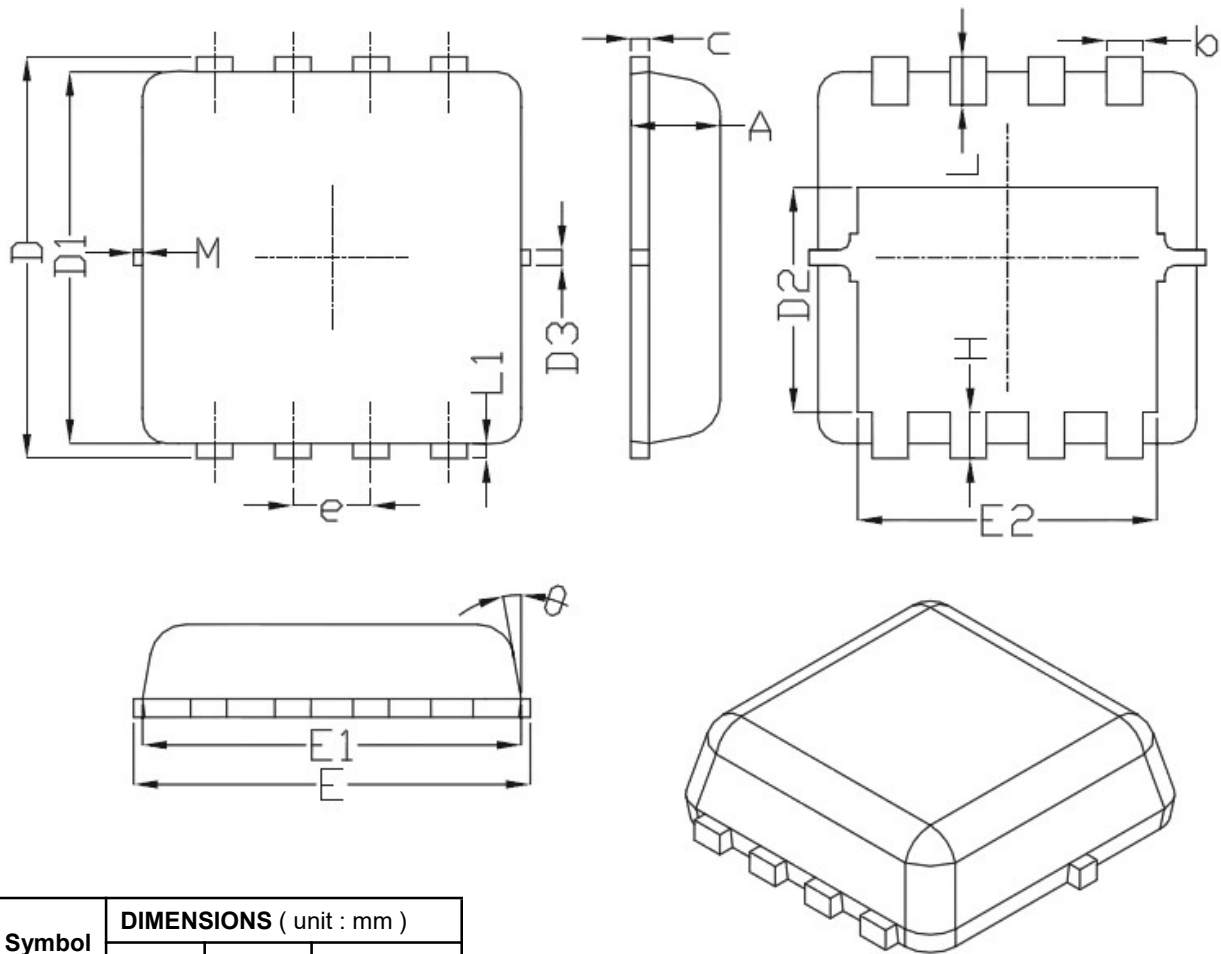
3rd line: Date code (XXXYWW)

XXX: Wafer Lot Number Code , code changed with Lot Number

Y: Year Code , refer to table below

WW: Week Code (01 to 53)

Code	C	D	E	F	G	H	J	K	L	M	N	P	Q	R	S	T
Year	2015	2016	2017	2018	2019	2020	2021	2022	2023	2024	2025	2026	2027	2028	2029	2030

PDFN3333 Package Outline Data


Symbol	DIMENSIONS (unit : mm)		
	Min	Typ	Max
A	0.70	0.75	0.80
b	0.25	0.30	0.35
C	0.10	0.15	0.25
D	3.25	3.35	3.45
D1	3.00	3.10	3.20
D2	1.78	1.88	1.98
D3	--	0.13	--
E	3.00	3.20	3.40
E1	3.00	3.10	3.20
E2	2.39	2.49	2.59
e	0.65 BSC		
H	0.30	0.39	0.50
L	0.30	0.40	0.50
L1	--	0.13	--
θ	--	10°	12°
M	*	*	0.15
* Not specified			

Notes:

1. Follow JEDEC MO-240 variation CA.
2. Dimensions "D1" and "E1" do NOT include mold flash protrusions or gate burrs.
3. Dimensions "D1" and "E1" include interterminal flash or protrusion. Interterminal flash or protrusion shall not exceed 0.25mm per side.

Customer Service
Sales and Service:
sales@vgsemi.com
Vergiga Semiconductor CO., LTD
TEL: (86-755) -26902410

FAX: (86-755) -26907027

WEB: www.vergiga.com